



PTO/SB/08A (07-05)

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**INFORMATION DISCLOSURE  
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Sheet 1

of

2

**Complete if Known**

Application Number	09/557,672
Filing Date	April 25, 2000
First Named Inventor	Michael K. BRAND
Art Unit	2128
Examiner Name	Thai Q. PHAN
Attorney Docket Number	12177/13401

**U.S. PATENT DOCUMENTS**

Examiner Initials *	Cite No. <sup>1</sup>	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
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**FOREIGN PATENT DOCUMENTS**

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**NON PATENT LITERATURE DOCUMENTS**

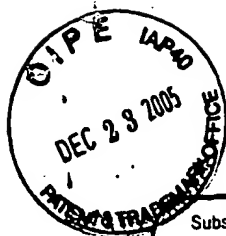
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T.P.	1	Siegel, B. "Reliability and the Electronic Engineer," Intersil Corporation Application Note AN1104, March 24, 1998. <a href="http://www.intersil.com/data/an/an1104.pdf">http://www.intersil.com/data/an/an1104.pdf</a>	
T.P.	2	Weibull.com, "Arrhenius Relationship Introduction," Printed from the 4/23/2001 archived version stored at Archive.org. <a href="http://web.archive.org/web/20010423072851/http://weibull.com/AccelTestWeb/arrhenius_relationship_introduction.htm">http://web.archive.org/web/20010423072851/http://weibull.com/AccelTestWeb/arrhenius_relationship_introduction.htm</a>	
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T.P.	4	Shih, C., Lambertson, R., et al., "Characterization and Modeling of a Highly Reliable Metal-to-Metal Antifuse for High-Performance and High-Density Field-Programmable Gate Arrays." 1997 IEEE Int'l Reliability Physics Symposium (IRPS), April 8, 1997	
T.P.	5	Technical Program of IRPS '97, pp. 1-2, April 8, 1997 <a href="http://www.irps.org/97-35th/tp97.html">http://www.irps.org/97-35th/tp97.html</a>	
T.P.	6	Internet Archive "Way Back Machine" search results for <a href="http://www.weibull.com/acctestwebcontents.htm">http://www.weibull.com/acctestwebcontents.htm</a>	
T.P.	7	Weibull.com, "Quantitative Accelerated Life Testing Data Analysis: An Overview of Basic Concepts" © 1992-2005 <a href="http://www.weibull.com/basics/accelerated.htm">http://www.weibull.com/basics/accelerated.htm</a>	
T.P.	8	Weibull.com, "Accelerated Life Testing On_line Reference Contents," Printed from the 6/13/2001 archived version stored at Archive.org. <a href="http://web.archive.org/web/20010613024105/http://weibull.com/acctestwebcontents.htm">http://web.archive.org/web/20010613024105/http://weibull.com/acctestwebcontents.htm</a>	

Examiner Signature	<i>thayphan</i>	Date Considered	6-1-2006
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Examiner Initials *	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T <sup>2</sup>
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	11	Weibull.com, "Arrhenius Exponential Statistical Properties Summary," Printed from the 3/4/2001 archived version stored at Archive.org <a href="http://web.archive.org/web/20010304055733/weibull.com/AccelTestWeb/arrhenius_exponential_statistical_properties.htm">http://web.archive.org/web/20010304055733/weibull.com/AccelTestWeb/arrhenius_exponential_statistical_properties.htm</a>	
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T.P.	13	Weibull.com, "Accelerated Life Testing," Printed from the 3/3/2001 archived version stored at Archive.org. <a href="http://web.archive.org/web/20010303041409/weibull.com/AccelTestWeb/accelerated_life_testing.htm">http://web.archive.org/web/20010303041409/weibull.com/AccelTestWeb/accelerated_life_testing.htm</a>	
T.P.	14	Weibull.com, "Types of Accelerated Tests," Printed from the 4/22/2001 archived version stored at Archive.org. <a href="http://web.archive.org/web/20010422214528/www.weibull.com/AccelTestWeb/types_of_accelerated_tests.htm">http://web.archive.org/web/20010422214528/www.weibull.com/AccelTestWeb/types_of_accelerated_tests.htm</a>	
T.P.	15	Weibull.com, "Quantitative Accelerated Life Tests," Printed from the 12/17/2001 archived version stored at Archive.org <a href="http://web.archive.org/web/20011217220235/www.weibull.com/AccelTestWeb/accelerated_life_tests.htm">http://web.archive.org/web/20011217220235/www.weibull.com/AccelTestWeb/accelerated_life_tests.htm</a>	

Examiner Signature	Thai Phan	Date Considered	06-01-2006
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